

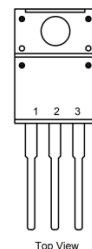
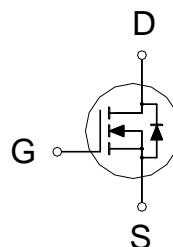
NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P0860JF**

TO-220F

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
600V	630m Ω	8A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	8	A
		5	
Pulsed Drain Current ¹	I_{DM}	13	A
Avalanche Current ³	I_{AS}	1.9	
Avalanche Energy ³	E_{AS}	130	mJ
Power Dissipation	P_D	25	W
		9.8	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	5.1	5.1	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Ensure that the channel temperature does not exceed 150°C.³ $V_{DD} = 50V$, $L = 75mH$, starting $T_J = 25^\circ C$.

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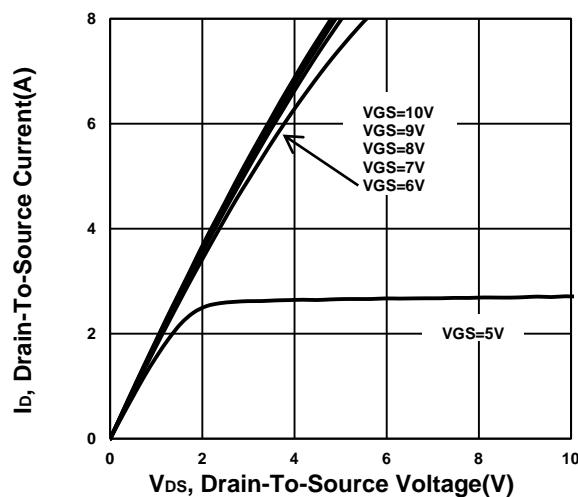
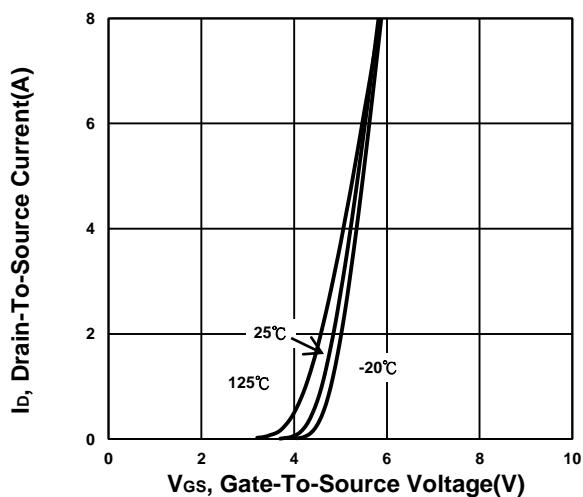
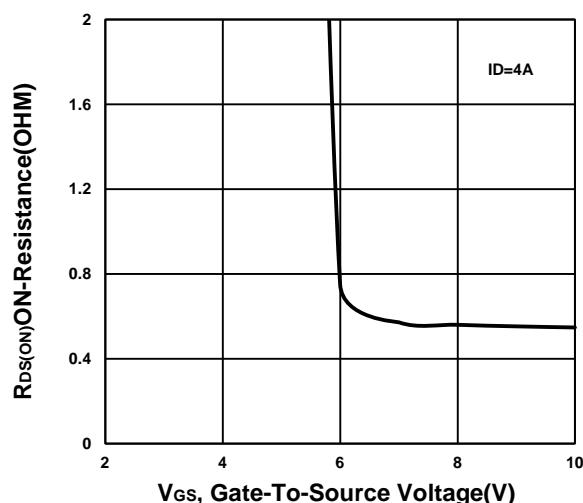
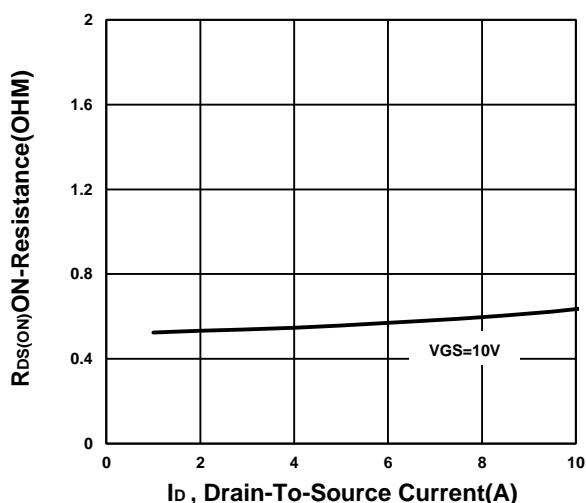
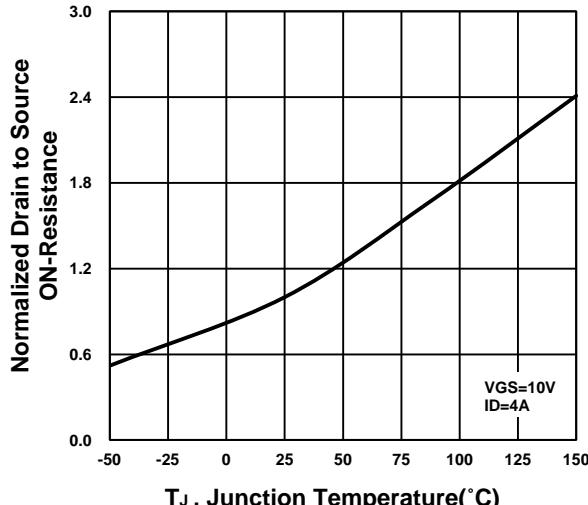
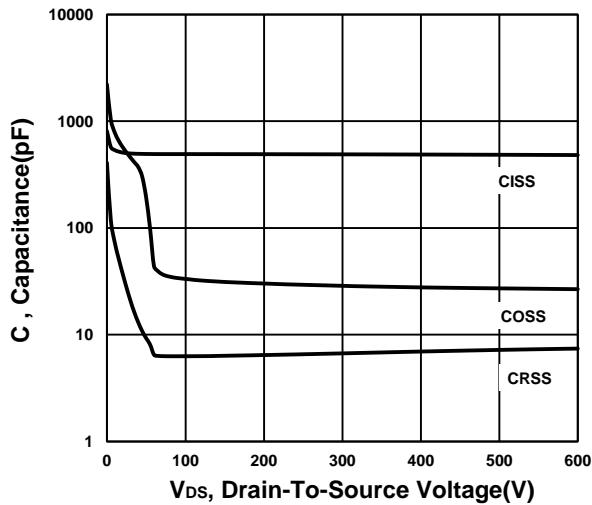
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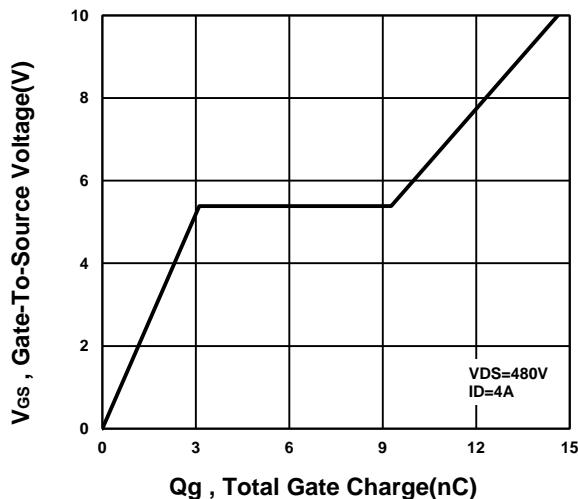
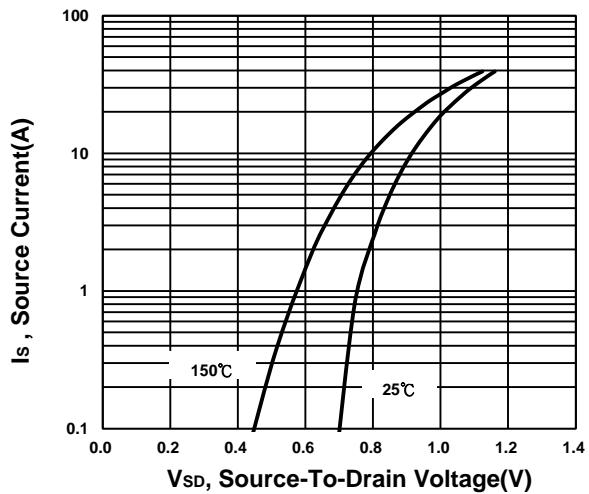
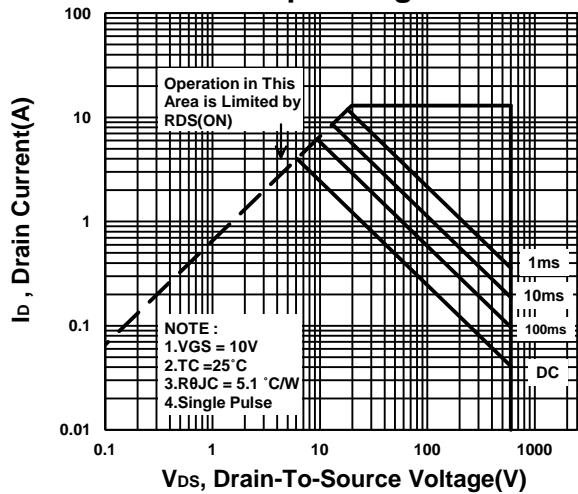
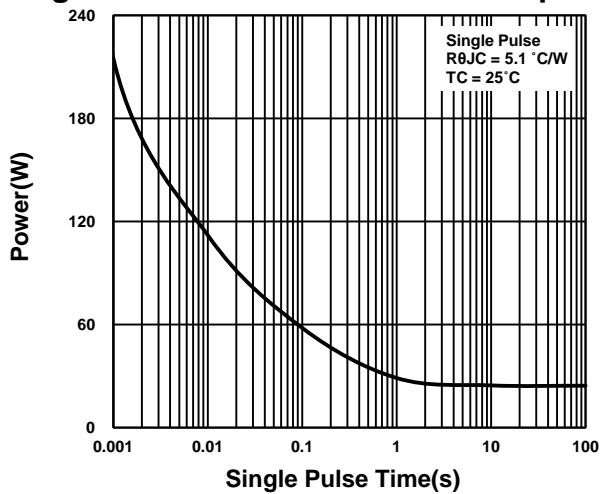
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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	600			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3.4	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600V, V_{GS} = 0V$			1	
		$V_{DS} = 480V, V_{GS} = 0V, T_J = 100^\circ C$			10	μA
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 4A$		547	630	$m\Omega$
Forward Transconductance ¹	g_{fs}	$V_{DS} = 15V, I_D = 4A$		61		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 100V, f = 250KHz$		486		pF
Output Capacitance	C_{oss}			32		
Reverse Transfer Capacitance	C_{rss}			6		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		26		Ω
Total Gate Charge ²	Q_g	$V_{DS} = 480V, V_{GS} = 10V, I_D = 4A$		15		nC
Gate-Source Charge ²	Q_{gs}			3.1		
Gate-Drain Charge ²	Q_{gd}			6.2		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 300V,$ $I_D \approx 4A, V_{GS} = 10V, R_{GEN} = 25\Omega$		12		nS
Rise Time ²	t_r			26		
Turn-Off Delay Time ²	$t_{d(off)}$			68		
Fall Time ²	t_f			50		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				8	A
Forward Voltage ¹	V_{SD}	$I_F = 8A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 4A, dI_F/dt = 100A/\mu s$		212		nS
Reverse Recovery Charge	Q_{rr}			1.8		uC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

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TO-220F
Halogen-Free & Lead-Free****Output Characteristics****Transfer Characteristics****On-Resistance VS Gate-To-Source Voltage****On-Resistance VS Drain Current****On-Resistance VS Temperature****Capacitance Characteristic**

NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P0860JF
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Halogen-Free & Lead-Free****Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**